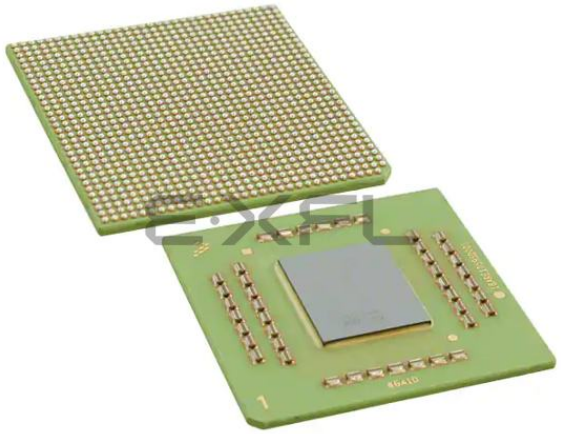

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Applications of Embedded - Microprocessors

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details	
Product Status	Obsolete
Core Processor	PowerPC e600
Number of Cores/Bus Width	2 Core, 32-Bit
Speed	1.333GHz
Co-Processors/DSP	-
RAM Controllers	DDR, DDR2
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (4)
SATA	-
USB	-
Voltage - I/O	1.8V, 2.5V, 3.3V
Operating Temperature	-40°C ~ 105°C (TA)
Security Features	-
Package / Case	1023-BBGA, FCBGA
Supplier Device Package	1023-FCCBGA (33x33)
Purchase URL	https://www.e-xfl.com/product-detail/nxp-semiconductors/mc8641dthx1333jc

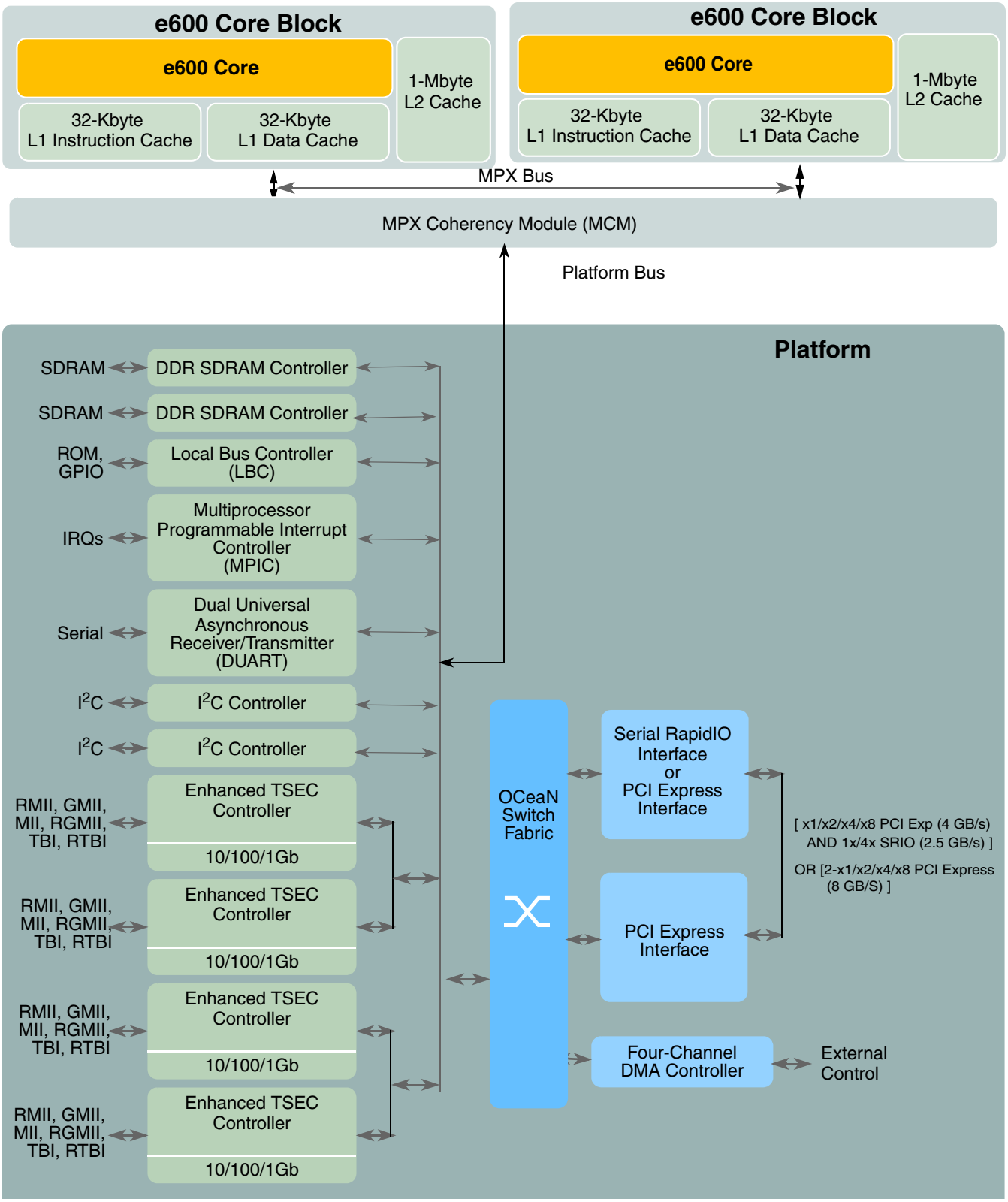


Figure 1. MPC8641 and MPC8641D

Table 1. Absolute Maximum Ratings[1] (continued)

Characteristic		Symbol	Absolute Maximum Value	Unit	Notes
Input voltage	DDR and DDR2 SDRAM signals	D*n*_MV_{IN}	– 0.3 to (D*n*_GV_{DD} + 0.3)	V	5
	DDR and DDR2 SDRAM reference	D*n*_MV_{REF}	– 0.3 to (D*n*_GV_{DD}/2 + 0.3)	V	—
	Three-speed Ethernet signals	LV_{IN} TV_{IN}	GND to (LV_{DD}+ 0.3) GND to (TV_{DD}+ 0.3)	V	5
	DUART, Local Bus, DMA, Multiprocessor Interrupts, System Control & Clocking, Debug, Test, Power management, I^2C, JTAG and Miscellaneous I/O voltage	OV_{IN}	GND to (OV_{DD}+ 0.3)	V	5
Storage temperature range		T_{STG}	–55 to 150	°C	—

Notes:

1. Functional and tested operating conditions are given in Table 2. Absolute maximum ratings are stress ratings only, and functional operation at the maxima is not guaranteed. Stresses beyond those listed may affect device reliability or cause permanent damage to the device.
2. Core 1 characteristics apply only to MPC8641D. If two separate power supplies are used for V_{DD}_Core0 and V_{DD}_Core1, they must be kept within 100 mV of each other during normal run time.
3. The –0.3 to 2.75 V range is for DDR and –0.3 to 1.98 V range is for DDR2.
4. The 3.63V maximum is only supported when the port is configured in GMII, MII, RMII, or TBI modes; otherwise the 2.75V maximum applies. See Section 8.2, "FIFO, GMII, MII, TBI, RGMII, RMII, and RTBI AC Timing Specifications," for details on the recommended operating conditions per protocol.
5. During run time (M,L,T,O)V_{IN} and D*n*_MV_{REF} may overshoot/undershoot to a voltage and for a maximum duration as shown in Figure 2.

2.1.2 Recommended Operating Conditions

Table 2 provides the recommended operating conditions for the MPC8641. Note that the values in Table 2 are the recommended and tested operating conditions. Proper device operation outside of these conditions is not guaranteed. For details on order information and specific operating conditions for parts, see Section 21, "Ordering Information."

Table 2. Recommended Operating Conditions

Characteristic	Symbol	Recommended Value	Unit	Notes
Cores supply voltages	V_{DD}_Core0, V_{DD}_Core1	1.10 ± 50 mV	V	1, 2, 8
		1.05 ± 50 mV		1, 2, 7
		0.95 ± 50 mV		1, 2, 12
Cores PLL supply	AV_{DD}_Core0, AV_{DD}_Core1	1.10 ± 50 mV	V	8, 13
		1.05 ± 50 mV		7, 13
		0.95 ± 50 mV		12, 13
SerDes Transceiver Supply (Ports 1 and 2)	SV_{DD}	1.10 ± 50 mV	V	8, 11
		1.05 ± 50 mV		7, 11

NOTE

There is no required order sequence between the individual rails for this item (# 1). However, V_{DD}_PLAT, AV_{DD}_PLAT rails must reach 90% of their recommended value before the rail for Dn_GV_{DD}, and Dn_MV_{REF} (in next step) reaches 10% of their recommended value. AV_{DD} type supplies must be delayed with respect to their source supplies by the RC time constant of the PLL filter circuit described in Section 20.2.1, "PLL Power Supply Filtering."

2. D*n*_GV_{DD}, D*n*_MV_{REF}

NOTE

It is possible to leave the related power supply (D*n*_GV_{DD}, D*n*_MV_{REF}) turned off at reset for a DDR port that will not be used. Note that these power supplies can only be powered up again at reset for functionality to occur on the DDR port.

3. SYSCLK

The recommended order of power down is as follows:

1. D*n*_GV_{DD}, D*n*_MV_{REF}
2. All power rails other than DDR I/O (D*n*_GV_{DD}, D*n*_MV_{REF}).

NOTE

SYSCLK may be powered down simultaneous to either of item # 1 or # 2 in the power down sequence. Beyond this, the power supplies may power down simultaneously if the preservation of DDR*n* memory is not a concern.

See Figure 3 for more details on the Power and Reset Sequencing details.

Table 15 provides the recommended operating conditions for the DDR SDRAM component(s) when D*n*_GV_{DD}(typ) = 2.5 V.

Table 15. DDR SDRAM DC Electrical Characteristics for D*n*_GV_{DD} (typ) = 2.5 V

Parameter/Condition	Symbol	Min	Max	Unit	Notes
I/O supply voltage	D*n*_GV_{DD}	2.375	2.625	V	1
I/O reference voltage	D*n*_MV_{REF}	0.49 × D*n*_GV_{DD}	0.51 × D*n*_GV_{DD}	V	2
I/O termination voltage	V_{TT}	D*n*_MV_{REF} – 0.04	D*n*_MV_{REF} + 0.04	V	3
Input high voltage	V_{IH}	D*n*_MV_{REF} + 0.15	D*n*_GV_{DD} + 0.3	V	—
Input low voltage	V_{IL}	–0.3	D*n*_MV_{REF}– 0.15	V	—
Output leakage current	I_{OZ}	–50	50	μA	4
Output high current (V_{OUT} = 1.95 V)	I_{OH}	–16.2	—	mA	—
Output low current (V_{OUT} = 0.35 V)	I_{OL}	16.2	—	mA	—

Notes:
1. D*n*_GV_{DD} is expected to be within 50 mV of the DRAM D*n*_GV_{DD} at all times.
2. MV_{REF} is expected to be equal to 0.5 × D*n*_GV_{DD}, and to track D*n*_GV_{DD} DC variations as measured at the receiver. Peak-to-peak noise on D*n*_MV_{REF} may not exceed ±2% of the DC value.
3. V_{TT} is not applied directly to the device. It is the supply to which far end signal termination is made and is expected to be equal to D*n*_MV_{REF}. This rail should track variations in the DC level of D*n*_MV_{REF}.
4. Output leakage is measured with all outputs disabled, 0 V ≤ V_{OUT} ≤ D*n*_GV_{DD}.

Table 16 provides the DDR capacitance when D*n*_GV_{DD} (typ)=2.5 V.

Table 16. DDR SDRAM Capacitance for D*n*_GV_{DD} (typ) = 2.5 V

Parameter/Condition	Symbol	Min	Max	Unit	Notes
Input/output capacitance: DQ, DQS	C_{IO}	6	8	pF	1
Delta input/output capacitance: DQ, DQS	C_{DIO}	—	0.5	pF	1

Note:
1. This parameter is sampled. D*n*_GV_{DD} = 2.5 V ± 0.125 V, f = 1 MHz, T_A = 25°C, V_{OUT} = D*n*_GVDD/2, V_{OUT} (peak-to-peak) = 0.2 V.

Table 17 provides the current draw characteristics for MV_{REF}.

Table 17. Current Draw Characteristics for MV_{REF}

Parameter / Condition	Symbol	Min	Max	Unit	Note
Current draw for MV_{REF}	I_{MVREF}	—	500	μA	1

1. The voltage regulator for MV_{REF} must be able to supply up to 500 μA current.

Figure 7 provides the AC test load for the DDR bus.

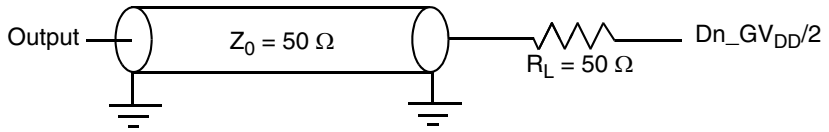


Figure 7. DDR AC Test Load

7 DUART

This section describes the DC and AC electrical specifications for the DUART interface of the MPC8641.

7.1 DUART DC Electrical Characteristics

Table 22 provides the DC electrical characteristics for the DUART interface.

Table 22. DUART DC Electrical Characteristics

Parameter	Symbol	Min	Max	Unit
High-level input voltage	V_{IH}	2	OV_{DD} + 0.3	V
Low-level input voltage	V_{IL}	–0.3	0.8	V
Input current (V_{IN} [1] = 0 V or V_{IN} = V_{DD})	I_{IN}	—	±5	μA
High-level output voltage (OV_{DD} = min, I_{OH} = –100 μA)	V_{OH}	OV_{DD} – 0.2	—	V
Low-level output voltage (OV_{DD} = min, I_{OL} = 100 μA)	V_{OL}	—	0.2	V

Note:
1. Note that the symbol V_{IN}, in this case, represents the OV_{IN} symbol referenced in Table 1 and Table 2.

7.2 DUART AC Electrical Specifications

Table 23 provides the AC timing parameters for the DUART interface.

Table 23. DUART AC Timing Specifications

Parameter	Value	Unit	Notes
Minimum baud rate	MPX clock/1,048,576	baud	1,2
Maximum baud rate	MPX clock/16	baud	1,3
Oversample rate	16	—	1,4

Notes:
1. Guaranteed by design.
2. MPX clock refers to the platform clock.
3. Actual attainable baud rate will be limited by the latency of interrupt processing.
4. The middle of a start bit is detected as the 8th sampled 0 after the 1-to-0 transition of the start bit. Subsequent bit values are sampled each 16th sample.

Table 39. MII Management AC Timing Specifications (continued)

At recommended operating conditions with OV_{DD} is 3.3 V ± 5%.

Parameter/Condition	Symbol [1]	Min	Typ	Max	Unit	Notes
MDIO to MDC hold time	t_{MDDXKH}	0	—	—	ns	—
MDC rise time	t_{MDCR}	—	—	10	ns	4
MDC fall time	t_{MDHF}	—	—	10	ns	4

Notes:

1. The symbols used for timing specifications herein follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{MDKHDX} symbolizes management data timing (MD) for the time t_{MDC} from clock reference (K) high (H) until data outputs (D) are invalid (X) or data hold time. Also, t_{MDDVKH} symbolizes management data timing (MD) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{MDC} clock reference (K) going to the high (H) state or setup time. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
2. This parameter is dependent on the system clock speed. (The maximum frequency is the maximum platform frequency divided by 64.)
3. This parameter is dependent on the system clock speed. (That is, for a system clock of 267 MHz, the maximum frequency is 8.3 MHz and the minimum frequency is 1.2 MHz; for a system clock of 375 MHz, the maximum frequency is 11.7 MHz and the minimum frequency is 1.7 MHz.)
4. Guaranteed by design.
5. t_{MPXCLK} is the platform (MPX) clock

Figure 23 provides the AC test load for eTSEC.

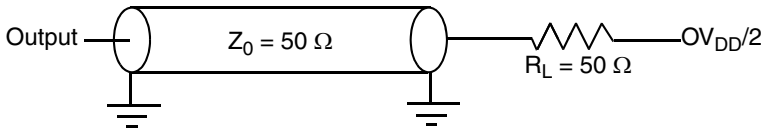


Figure 23. eTSEC AC Test Load

NOTE

Output will see a 50-Ω load since what it sees is the transmission line.

Figure 24 shows the MII management AC timing diagram.

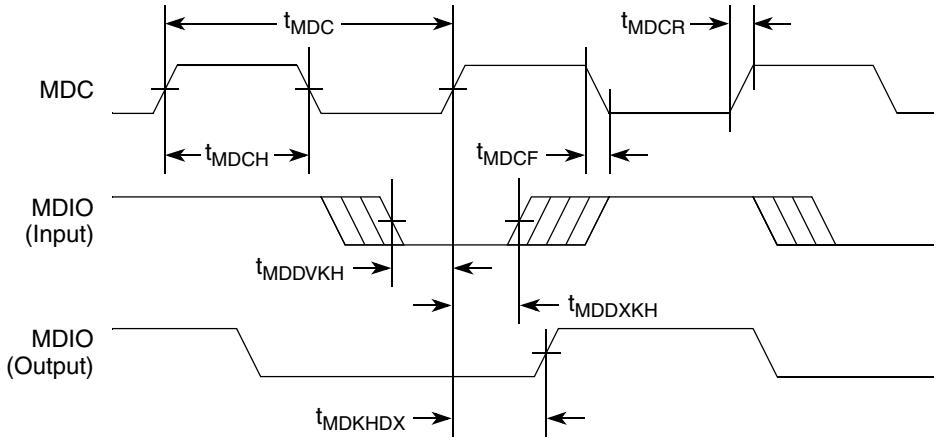


Figure 24. MII Management Interface Timing Diagram

Table 41. Local Bus Timing Parameters (OV_{DD} = 3.3 V)m - PLL Enabled (continued)

Parameter	Symbol [1]	Min	Max	Unit	Notes
Local bus clock to LALE assertion	$t_{LBKHOV4}$	—	2.3	ns	3
Output hold from local bus clock (except LAD/LDP and LALE)	$t_{LBKHOX1}$	0.7	—	ns	—
Output hold from local bus clock for LAD/LDP	$t_{LBKHOX2}$	0.7	—	ns	3
Local bus clock to output high Impedance (except LAD/LDP and LALE)	$t_{LBKHOZ1}$	—	2.5	ns	5
Local bus clock to output high impedance for LAD/LDP	$t_{LBKHOZ2}$	—	2.5	ns	5

Note:

1. The symbols used for timing specifications herein follow the pattern of $t_{\text{(First two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(First two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, $t_{LBIXKH1}$ symbolizes local bus timing (LB) for the input (I) to go invalid (X) with respect to the time the t_{LBK} clock reference (K) goes high (H), in this case for clock one(1). Also, t_{LBKHOX} symbolizes local bus timing (LB) for the t_{LBK} clock reference (K) to go high (H), with respect to the output (O) going invalid (X) or output hold time.
2. All timings are in reference to LSYNC_IN for PLL enabled and internal local bus clock for PLL bypass mode.
3. All signals are measured from $OV_{DD}/2$ of the rising edge of LSYNC_IN for PLL enabled or internal local bus clock for PLL bypass mode to $0.4 \times OV_{DD}$ of the signal in question for 3.3-V signaling levels.
4. Input timings are measured at the pin.
5. For purposes of active/float timing measurements, the Hi-Z or off state is defined to be when the total current delivered through the component pin is less than or equal to the leakage current specification.
6. t_{LBOTOT} is a measurement of the minimum time between the negation of LALE and any change in LAD. t_{LBOTOT} is programmed with the LBCR[AHD] parameter.
7. Maximum possible clock skew between a clock LCLK[m] and a relative clock LCLK[n]. Skew measured between complementary signals at $BV_{DD}/2$.
8. Guaranteed by design.

Figure 25 provides the AC test load for the local bus.

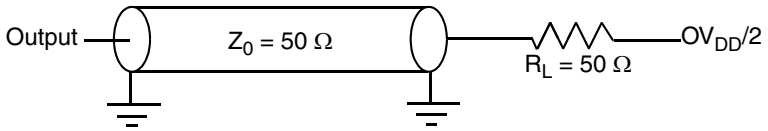


Figure 25. Local Bus AC Test Load

Table 42. Local Bus Timing Parameters—PLL Bypassed (continued)

Parameter	Symbol [1]	Min	Max	Unit	Notes
$\overline{\text{LGTA}}$/LUPWAIT input hold from local bus clock	$t_{LBIXKL2}$	–1.3	—	ns	4, 5
LALE output transition to LAD/LDP output transition (LATCH hold time)	t_{LBOTOT}	1.5	—	ns	6
Local bus clock to output valid (except LAD/LDP and LALE)	$t_{LBKLOV1}$	—	–0.3	ns	
Local bus clock to data valid for LAD/LDP	$t_{LBKLOV2}$	—	–0.1	ns	4
Local bus clock to address valid for LAD	$t_{LBKLOV3}$	—	0	ns	4
Local bus clock to LALE assertion	$t_{LBKLOV4}$	—	0	ns	4
Output hold from local bus clock (except LAD/LDP and LALE)	$t_{LBKLOX1}$	–3.2	—	ns	4
Output hold from local bus clock for LAD/LDP	$t_{LBKLOX2}$	–3.2	—	ns	4
Local bus clock to output high Impedance (except LAD/LDP and LALE)	$t_{LBKLOZ1}$	—	0.2	ns	7
Local bus clock to output high impedance for LAD/LDP	$t_{LBKLOZ2}$	—	0.2	ns	7

Notes:

1. The symbols used for timing specifications herein follow the pattern of $t_{\text{(First two letters of functional block)(signal)(state) (reference)(state)}}$ for inputs and $t_{\text{(First two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, $t_{LBIXKH1}$ symbolizes local bus timing (LB) for the input (I) to go invalid (X) with respect to the time the t_{LBK} clock reference (K) goes high (H), in this case for clock one(1). Also, t_{LBKHOX} symbolizes local bus timing (LB) for the t_{LBK} clock reference (K) to go high (H), with respect to the output (O) going invalid (X) or output hold time.
2. All timings are in reference to local bus clock for PLL bypass mode. Timings may be negative with respect to the local bus clock because the actual launch and capture of signals is done with the internal launch/capture clock, which precedes LCLK by t_{LBKHKT}.
3. Maximum possible clock skew between a clock LCLK[m] and a relative clock LCLK[n]. Skew measured between complementary signals at $BV_{DD}/2$.
4. All signals are measured from BVDD/2 of the rising edge of local bus clock for PLL bypass mode to 0.4 x BVDD of the signal in question for 3.3-V signaling levels.
5. Input timings are measured at the pin.
6. The value of t_{LBOTOT} is the measurement of the minimum time between the negation of LALE and any change in LAD
7. For purposes of active/float timing measurements, the Hi-Z or off state is defined to be when the total current delivered through the component pin is less than or equal to the leakage current specification.
8. Guaranteed by characterization.

Table 46. I²C AC Electrical Specifications (continued)

All values refer to V_{IH} (min) and V_{IL} (max) levels (see Table 45).

Parameter	Symbol [1]	Min	Max	Unit
Noise margin at the HIGH level for each connected device (including hysteresis)	V_{NH}	$0.2 \times OV_{DD}$	—	V

Note:

1. The symbols used for timing specifications herein follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state) (reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{I2DVKH} symbolizes I²C timing (I2) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{I2C} clock reference (K) going to the high (H) state or setup time. Also, t_{I2SXKL} symbolizes I²C timing (I2) for the time that the data with respect to the start condition (S) went invalid (X) relative to the t_{I2C} clock reference (K) going to the low (L) state or hold time. Also, t_{I2PVKH} symbolizes I²C timing (I2) for the time that the data with respect to the stop condition (P) reaching the valid state (V) relative to the t_{I2C} clock reference (K) going to the high (H) state or setup time. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
2. As a transmitter, the MPC8641 provides a delay time of at least 300 ns for the SDA signal (referred to the Vihmin of the SCL signal) to bridge the undefined region of the falling edge of SCL to avoid unintended generation of Start or Stop condition. When MPC8641 acts as the I²C bus master while transmitting, MPC8641 drives both SCL and SDA. As long as the load on SCL and SDA are balanced, MPC8641 would not cause unintended generation of Start or Stop condition. Therefore, the 300 ns SDA output delay time is not a concern. If, under some rare condition, the 300 ns SDA output delay time is required for MPC8641 as transmitter, the following setting is recommended for the FDR bit field of the I2CFDR register to ensure both the desired I²C SCL clock frequency and SDA output delay time are achieved, assuming that the desired I²C SCL clock frequency is 400 KHz and the Digital Filter Sampling Rate Register (I2CDFSRR) is programmed with its default setting of 0x10 (decimal 16):

I²C Source Clock Frequency	333 MHz	266 MHz	200 MHz	133 MHz
FDR Bit Setting	0x2A	0x05	0x26	0x00
Actual FDR Divider Selected	896	704	512	384
Actual I²C SCL Frequency Generated	371 KHz	378 KHz	390 KHz	346 KHz

   For the detail of I²C frequency calculation, refer to the application note AN2919 “Determining the I²C Frequency Divider Ratio for SCL”. Note that the I²C Source Clock Frequency is half of the MPX clock frequency for MPC8641.
3. The maximum t_{I2DXKL} has only to be met if the device does not stretch the LOW period (t_{I2CL}) of the SCL signal.
4. Guaranteed by design.
5. C_B = capacitance of one bus line in pF.

Figure 32 provides the AC test load for the I²C.

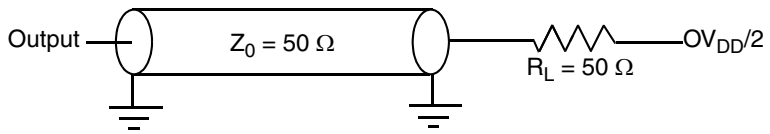


Figure 36. I²C AC Test Load

To illustrate these definitions using real values, consider the case of a CML (Current Mode Logic) transmitter that has a common mode voltage of 2.25 V and each of its outputs, TD and $\overline{\text{TD}}$, has a swing that goes between 2.5 V and 2.0 V. Using these values, the peak-to-peak voltage swing of each signal (TD or $\overline{\text{TD}}$) is 500 mV p-p, which is referred as the single-ended swing for each signal. In this example, since the differential signaling environment is fully symmetrical, the transmitter output's differential swing (V_{OD}) has the same amplitude as each signal's single-ended swing. The differential output signal ranges between 500 mV and –500 mV, in other words, V_{OD} is 500 mV in one phase and –500 mV in the other phase. The peak differential voltage (V_{DIFFp}) is 500 mV. The peak-to-peak differential voltage ($V_{DIFFp-p}$) is 1000 mV p-p.

13.2 SerDes Reference Clocks

The SerDes reference clock inputs are applied to an internal PLL whose output creates the clock used by the corresponding SerDes lanes. The SerDes reference clocks inputs are SD*n*_REF_CLK and $\overline{\text{SD}n\text{\_REF\_CLK}}$ for PCI Express and Serial RapidIO.

The following sections describe the SerDes reference clock requirements and some application information.

13.2.1 SerDes Reference Clock Receiver Characteristics

Figure 39 shows a receiver reference diagram of the SerDes reference clocks.

- The supply voltage requirements for XV_{DD}_SRDS*n* are specified in Table 1 and Table 2.
- SerDes Reference Clock Receiver Reference Circuit Structure
  - The SD*n*_REF_CLK and $\overline{\text{SD}n\text{\_REF\_CLK}}$ are internally AC-coupled differential inputs as shown in Figure 39. Each differential clock input (SD*n*_REF_CLK or $\overline{\text{SD}n\text{\_REF\_CLK}}$) has a 50-Ω termination to SGND followed by on-chip AC-coupling.
  - The external reference clock driver must be able to drive this termination.
  - The SerDes reference clock input can be either differential or single-ended. Refer to the Differential Mode and Single-ended Mode description below for further detailed requirements.
- The maximum average current requirement that also determines the common mode voltage range
  - When the SerDes reference clock differential inputs are DC coupled externally with the clock driver chip, the maximum average current allowed for each input pin is 8 mA. In this case, the exact common mode input voltage is not critical as long as it is within the range allowed by the maximum average current of 8 mA (refer to the following bullet for more detail), since the input is AC-coupled on-chip.
  - This current limitation sets the maximum common mode input voltage to be less than 0.4 V (0.4 V/50 = 8 mA) while the minimum common mode input level is 0.1 V above SGND. For example, a clock with a 50/50 duty cycle can be produced by a clock driver with output driven by its current source from 0 mA to 16 mA (0–0.8 V), such that each phase of the differential input has a single-ended swing from 0 V to 800 mV with the common mode voltage at 400 mV.
  - If the device driving the SD*n*_REF_CLK and $\overline{\text{SD}n\text{\_REF\_CLK}}$ inputs cannot drive 50 Ω to SGND DC, or it exceeds the maximum input current limitations, then it must be AC-coupled off-chip.

- The input amplitude requirement
  - This requirement is described in detail in the following sections.

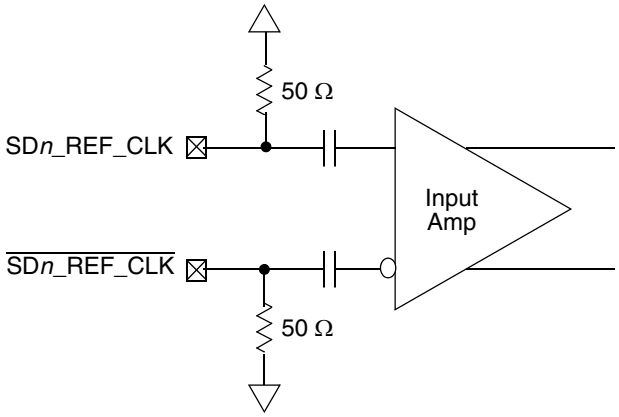


Figure 39. Receiver of SerDes Reference Clocks

13.2.2 DC Level Requirement for SerDes Reference Clocks

The DC level requirement for the MPC8641D SerDes reference clock inputs is different depending on the signaling mode used to connect the clock driver chip and SerDes reference clock inputs as described below.

- **Differential Mode**
  - The input amplitude of the differential clock must be between 400 mV and 1600 mV differential peak-peak (or between 200 mV and 800 mV differential peak). In other words, each signal wire of the differential pair must have a single-ended swing less than 800mV and greater than 200 mV. This requirement is the same for both external DC-coupled or AC-coupled connection.
  - For **external DC-coupled** connection, as described in Section 13.2.1, "SerDes Reference Clock Receiver Characteristics," the maximum average current requirements sets the requirement for average voltage (common mode voltage) to be between 100 mV and 400 mV. Figure 40 shows the SerDes reference clock input requirement for DC-coupled connection scheme.
  - For **external AC-coupled** connection, there is no common mode voltage requirement for the clock driver. Since the external AC-coupling capacitor blocks the DC level, the clock driver and the SerDes reference clock receiver operate in different command mode voltages. The SerDes reference clock receiver in this connection scheme has its common mode voltage set to SGND. Each signal wire of the differential inputs is allowed to swing below and above the command mode voltage (SGND). Figure 41 shows the SerDes reference clock input requirement for AC-coupled connection scheme.
- **Single-ended Mode**
  - The reference clock can also be single-ended. The SD*n*_REF_CLK input amplitude (single-ended swing) must be between 400 mV and 800 mV peak-peak (from Vmin to Vmax) with $\overline{\text{SD}n\text{\_REF\_CLK}}$ either left unconnected or tied to ground.

— The SD*n*_REF_CLK input average voltage must be between 200 and 400 mV. Figure 42 shows the SerDes reference clock input requirement for single-ended signaling mode.

— To meet the input amplitude requirement, the reference clock inputs might need to be DC or AC-coupled externally. For the best noise performance, the reference of the clock could be DC or AC-coupled into the unused phase ($\overline{\text{SD}n\text{\_REF\_CLK}}$) through the same source impedance as the clock input (SD*n*_REF_CLK) in use.

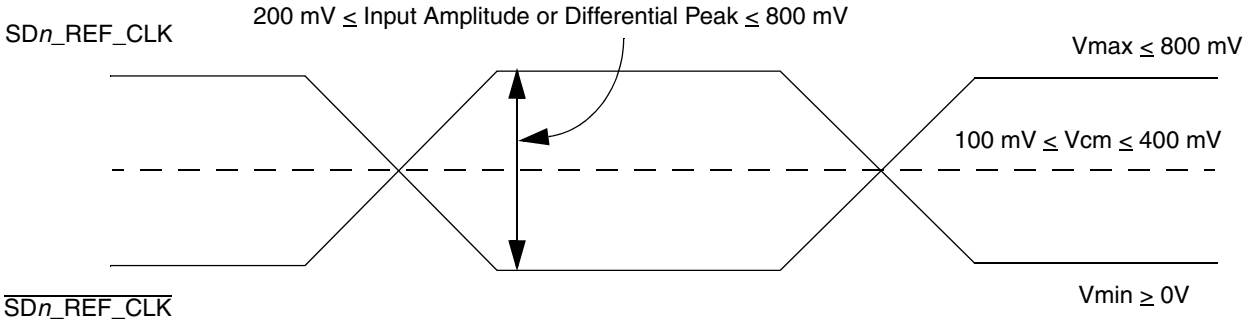


Figure 40. Differential Reference Clock Input DC Requirements (External DC-Coupled)

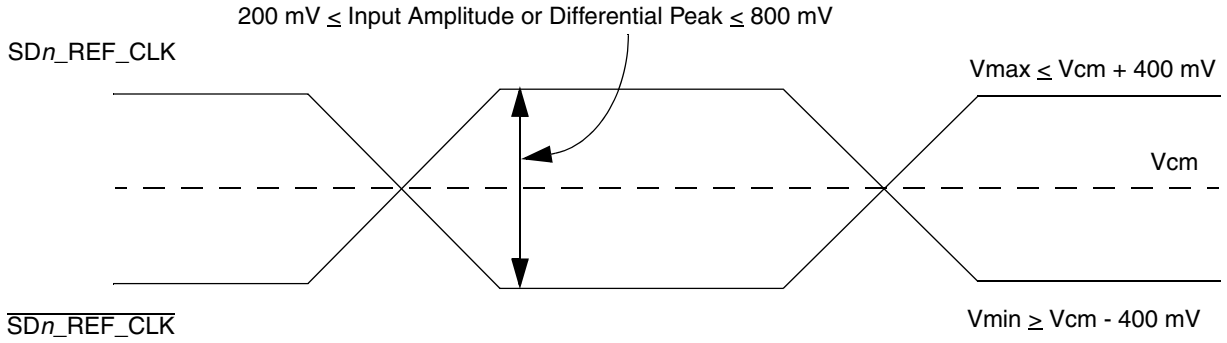


Figure 41. Differential Reference Clock Input DC Requirements (External AC-Coupled)

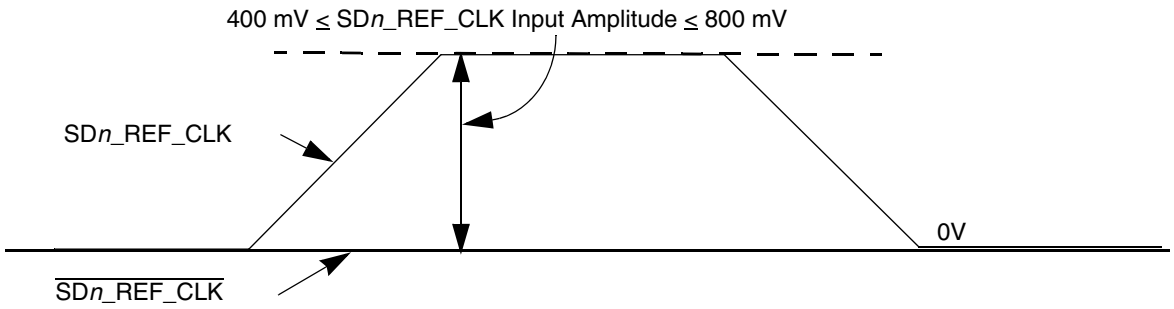


Figure 42. Single-Ended Reference Clock Input DC Requirements

MPC8641D SerDes reference clock input's DC requirement, AC-coupling has to be used. Figure 45 assumes that the LVPECL clock driver's output impedance is 50 Ω. R1 is used to DC-bias the LVPECL outputs prior to AC-coupling. Its value could be ranged from 140 Ω to 240 Ω depending on clock driver vendor's requirement. R2 is used together with the SerDes reference clock receiver's 50-Ω termination resistor to attenuate the LVPECL output's differential peak level such that it meets the MPC8641D SerDes reference clock's differential input amplitude requirement (between 200 mV and 800 mV differential peak). For example, if the LVPECL output's differential peak is 900 mV and the desired SerDes reference clock input amplitude is selected as 600mV, the attenuation factor is 0.67, which requires R2 = 25 Ω. Please consult clock driver chip manufacturer to verify whether this connection scheme is compatible with a particular clock driver chip.

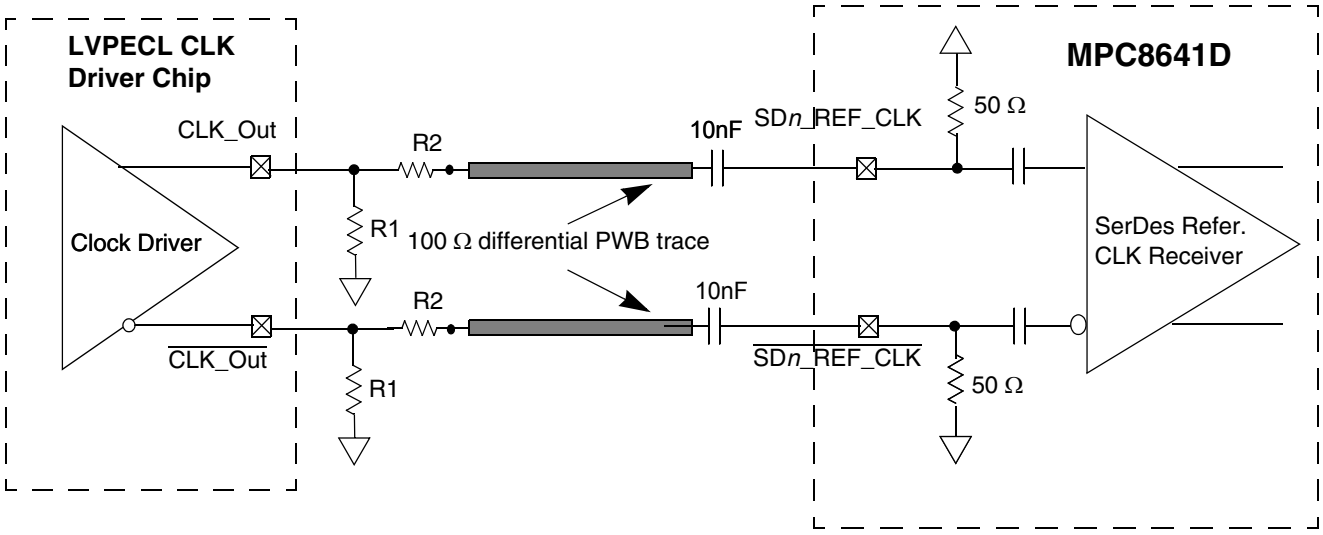


Figure 45. AC-Coupled Differential Connection with LVPECL Clock Driver (Reference Only)

Figure 46 shows the SerDes reference clock connection reference circuits for a single-ended clock driver. It assumes the DC levels of the clock driver are compatible with MPC8641D SerDes reference clock input's DC requirement.

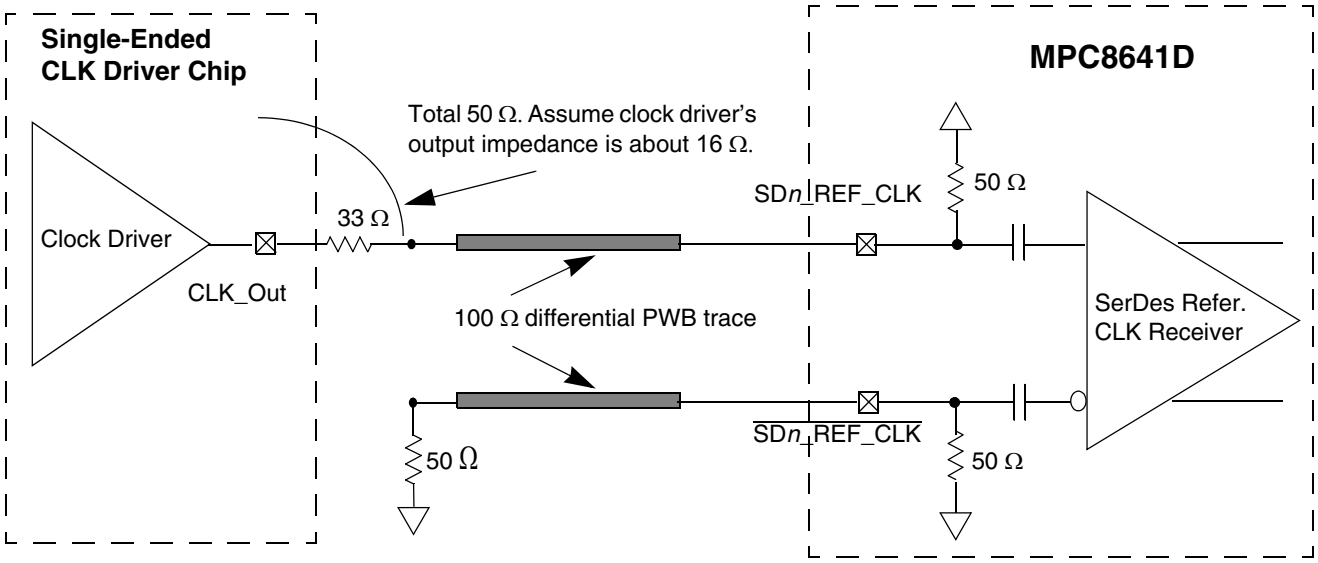


Figure 46. Single-Ended Connection (Reference Only)

14.1 DC Requirements for PCI Express SD*n*_REF_CLK and $\overline{\text{SD}n\text{\_REF\_CLK}}$

For more information, see Section 13.2, "SerDes Reference Clocks."

14.2 AC Requirements for PCI Express SerDes Clocks

Table 48 lists AC requirements.

Table 48. SD*n*_REF_CLK and $\overline{\text{SD}n\text{\_REF\_CLK}}$ AC Requirements

Symbol	Parameter Description	Min	Typical	Max	Units	Notes
t_{REF}	REFCLK cycle time	—	10	—	ns	—
t_{REFCJ}	REFCLK cycle-to-cycle jitter. Difference in the period of any two adjacent REFCLK cycles	—	—	100	ps	—
t_{REFPJ}	Phase jitter. Deviation in edge location with respect to mean edge location	–50	—	50	ps	—

14.3 Clocking Dependencies

The ports on the two ends of a link must transmit data at a rate that is within 600 parts per million (ppm) of each other at all times. This is specified to allow bit rate clock sources with a +/– 300 ppm tolerance.

14.4 Physical Layer Specifications

The following is a summary of the specifications for the physical layer of PCI Express on this device. For further details as well as the specifications of the Transport and Data Link layer please use the PCI EXPRESS Base Specification. REV. 1.0a document.

14.4.1 Differential Transmitter (TX) Output

Table 49 defines the specifications for the differential output at all transmitters (TXs). The parameters are specified at the component pins.

Table 49. Differential Transmitter (TX) Output Specifications

Symbol	Parameter	Min	Nom	Max	Units	Comments
UI	Unit Interval	399.88	400	400.12	ps	Each UI is 400 ps ± 300 ppm. UI does not account for Spread Spectrum Clock dictated variations. See Note 1.
$V_{TX\text{-}DIFFp\text{-}p}$	Differential Peak-to-Peak Output Voltage	0.8	—	1.2	V	$V_{TX\text{-}DIFFp\text{-}p} = 2*\lvert V_{TX\text{-}D+} - V_{TX\text{-}D-}\rvert$ See Note 2.
$V_{TX\text{-}DE\text{-}RATIO}$	De- Emphasized Differential Output Voltage (Ratio)	–3.0	–3.5	–4.0	dB	Ratio of the $V_{TX\text{-}DIFFp\text{-}p}$ of the second and following bits after a transition divided by the $V_{TX\text{-}DIFFp\text{-}p}$ of the first bit after a transition. See Note 2.

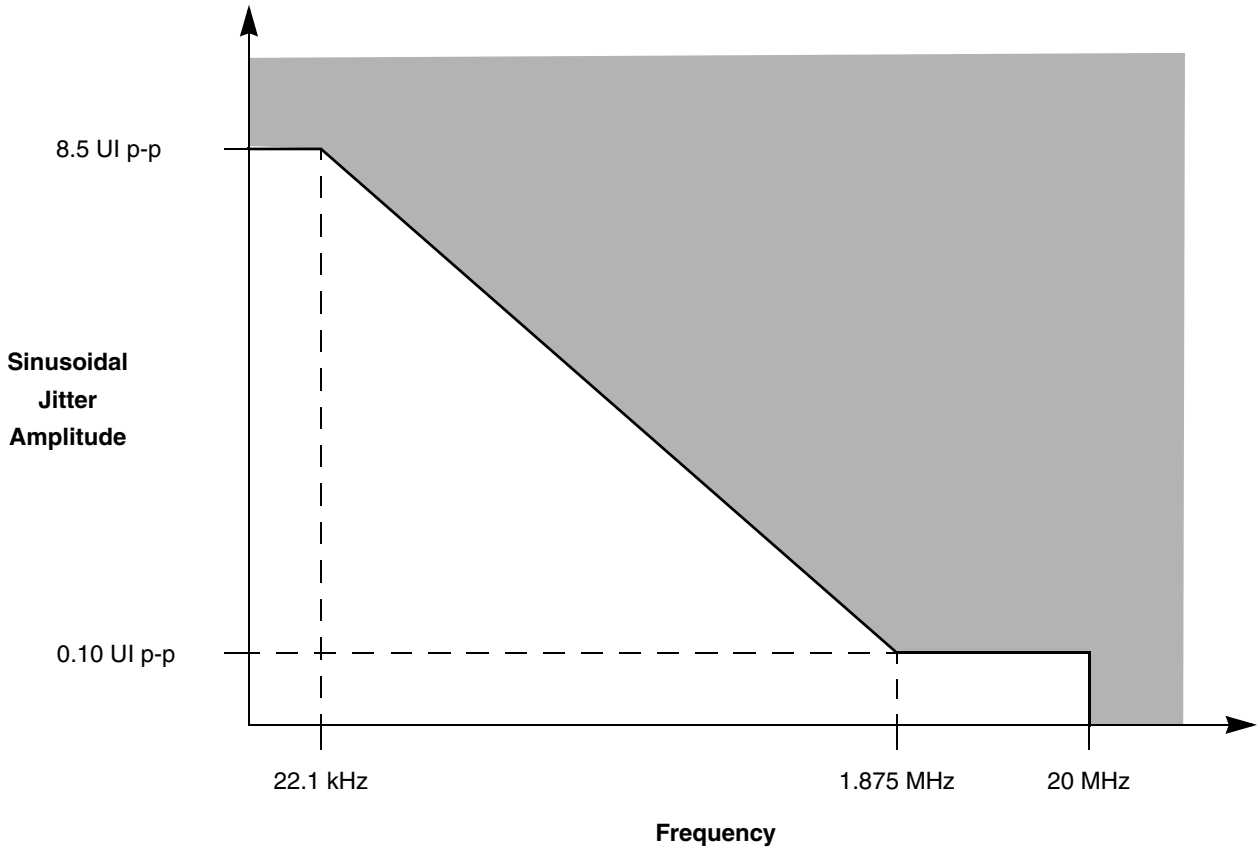


Figure 55. Single Frequency Sinusoidal Jitter Limits

15.8 Receiver Eye Diagrams

For each baud rate at which an LP-Serial receiver is specified to operate, the receiver shall meet the corresponding Bit Error Rate specification (Table 59, Table 60, Table 61) when the eye pattern of the receiver test signal (exclusive of sinusoidal jitter) falls entirely within the unshaded portion of the Receiver Input Compliance Mask shown in Figure 56 with the parameters specified in Table . The eye pattern of the receiver test signal is measured at the input pins of the receiving device with the device replaced with a 100 Ω +/– 5% differential resistive load.

Table 63. MPC8641 Signal Reference by Functional Block (continued)

Name[1]	Package Pin Number	Pin Type	Power Supply	Notes
TSEC3_TX_EN	AH19	O	TV_{DD}	36
TSEC3_TX_ER	AH17	O	TV_{DD}	—
TSEC3_TX_CLK	AH18	I	TV_{DD}	40
TSEC3_GTX_CLK	AG19	O	TV_{DD}	41
TSEC3_CRS	AE15	I/O	TV_{DD}	37
TSEC3_COL	AF15	I	TV_{DD}	—
TSEC3_RXD[0:7]	AJ17, AE16, AH16, AH14, AJ19, AH15, AG16, AE19	I	TV_{DD}	—
TSEC3_RX_DV	AG15	I	TV_{DD}	—
TSEC3_RX_ER	AF16	I	TV_{DD}	—
TSEC3_RX_CLK	AJ18	I	TV_{DD}	40
eTSEC Port 4 Signals[5]				
TSEC4_TXD[0:3]	AC18, AC16, AD18, AD17	O	TV_{DD}	6
TSEC4_TXD[4]	AD16	O	TV_{DD}	25
TSEC4_TXD[5:7]	AB18, AB17, AB16	O	TV_{DD}	6
TSEC4_TX_EN	AF17	O	TV_{DD}	36
TSEC4_TX_ER	AF19	O	TV_{DD}	—
TSEC4_TX_CLK	AF18	I	TV_{DD}	40
TSEC4_GTX_CLK	AG17	O	TV_{DD}	41
TSEC4_CRS	AB14	I/O	TV_{DD}	37
TSEC4_COL	AC13	I	TV_{DD}	—
TSEC4_RXD[0:7]	AG14, AD13, AF13, AD14, AE14, AB15, AC14, AE17	I	TV_{DD}	—
TSEC4_RX_DV	AC15	I	TV_{DD}	—
TSEC4_RX_ER	AF14	I	TV_{DD}	—
TSEC4_RX_CLK	AG13	I	TV_{DD}	40
Local Bus Signals[5]				
LAD[0:31]	A30, E29, C29, D28, D29, H25, B29, A29, C28, L22, M22, A28, C27, H26, G26, B27, B26, A27, E27, G25, D26, E26, G24, F27, A26, A25, C25, H23, K22, D25, F25, H22	I/O	OV_{DD}	6
LDP[0:3]	A24, E24, C24, B24	I/O	OV_{DD}	6, 22
LA[27:31]	J21, K21, G22, F24, G21	O	OV_{DD}	6, 22
$\overline{\text{LCS}}$[0:4]	A22, C22, D23, E22, A23	O	OV_{DD}	7
$\overline{\text{LCS}}$[5]/$\overline{\text{DMA\_DREQ}}$[2]	B23	O	OV_{DD}	7, 9, 10

Table 63. MPC8641 Signal Reference by Functional Block (continued)

Name[1]	Package Pin Number	Pin Type	Power Supply	Notes

Note:

1. Multi-pin signals such as D1_MDQ[0:63] and D2_MDQ[0:63] have their physical package pin numbers listed in order corresponding to the signal names.
2. Stub Series Terminated Logic (SSTL-18 and SSTL-25) type pins.
3. If a DDR port is not used, it is possible to leave the related power supply (Dn_GVDD, Dn_MVREF) turned off at reset. Note that these power supplies can only be powered up again at reset for functionality to occur on the DDR port.
4. Low Voltage Differential Signaling (LVDS) type pins.
5. Low Voltage Transistor-Transistor Logic (LVTTL) type pins.
6. This pin is a reset configuration pin and appears again in the Reset Configuration Signals section of this table. See the Reset Configuration Signals section of this table for config name and connection details.
7. Recommend a weak pull-up resistor (1–10 kΩ) be placed from this pin to its power supply.
8. Recommend a weak pull-down resistor (2–10 kΩ) be placed from this pin to ground.
9. This multiplexed pin has input status in one mode and output in another
10. This pin is a multiplexed signal for different functional blocks and appears more than once in this table.
11. This pin is open drain signal.
12. Functional only on the MPC8641D.
13. These pins should be left floating.
14. These pins should be connected to SV_{DD}.
15. These pins should be pulled to ground with a strong resistor (270-Ω to 330-Ω).
16. These pins should be connected to OVDD.
17. This is a SerDes PLL/DLL digital test signal and is only for factory use.
18. This is a SerDes PLL/DLL analog test signal and is only for factory use.
19. This pin should be pulled to ground with a 100-Ω resistor.
20. The pins in this section are reset configuration pins. Each pin has a weak internal pull-up P-FET which is enabled only when the processor is in the reset state. This pull-up is designed such that it can be overpowered by an external 4.7-kΩ pull-down resistor. However, if the signal is intended to be high after reset, and if there is any device on the net which might pull down the value of the net at reset, then a pullup or active driver is needed.
21. Should be pulled down at reset if platform frequency is at 400 MHz.
22. These pins require 4.7-kΩ pull-up or pull-down resistors and must be driven as they are used to determine PLL configuration ratios at reset.
23. This output is actively driven during reset rather than being tri-stated during reset.
24 These JTAG pins have weak internal pull-up P-FETs that are always enabled.
25. This pin should NOT be pulled down (or driven low) during reset.
26. These are test signals for factory use only and must be pulled up (100-Ω to 1- kΩ) to OVDD for normal machine operation.
27. Dn_MDIC[0] should be connected to ground with an 18-Ω resistor +/– 1-Ω and Dn_MDIC[1] should be connected Dn_GVDD with an 18-Ω resistor +/– 1-Ω. These pins are used for automatic calibration of the DDR IOs.
28. Pin N18 is recommended as a reference point for determining the voltage of V_{DD}_PLAT and is hence considered as the V_{DD}_PLAT sensing voltage and is called SENSEVDD_PLAT.
29. Pin P18 is recommended as the ground reference point for SENSEVDD_PLAT and is called SENSEVSS_PLAT.
30. This pin should be pulled to ground with a 200-Ω resistor.
31. These pins are connected to the power/ground planes internally and may be used by the core power supply to improve tracking and regulation.
32. Must be tied low if unused
33. These pins may be used as defined functional reset configuration pins in the future. Please include a resistor pull up/down option to allow flexibility of future designs.
34. Used as serial data output for SRIO 1x/4x link.
35. Used as serial data input for SRIO 1x/4x link.
36. This pin requires an external 4.7-kΩ pull-down resistor to pevent PHY from seeing a valid Transmit Enable before it is actively driven.

19 Thermal

This section describes the thermal specifications of the MPC8641.

19.1 Thermal Characteristics

Table 71 provides the package thermal characteristics for the MPC8641.

Table 71. Package Thermal Characteristics[1]

Characteristic	Symbol	Value	Unit	Notes
Junction-to-ambient thermal resistance, natural convection, single-layer (1s) board	$R_{\theta JA}$	18	°C/W	1, 2
Junction-to-ambient thermal resistance, natural convection, four-layer (2s2p) board	$R_{\theta JA}$	13	°C/W	1, 3
Junction-to-ambient thermal resistance, 200 ft/min airflow, single-layer (1s) board	$R_{\theta JMA}$	13	°C/W	1, 3
Junction-to-ambient thermal resistance, 200 ft/min airflow, four-layer (2s2p) board	$R_{\theta JMA}$	9	°C/W	1, 3
Junction-to-board thermal resistance	$R_{\theta JB}$	5	°C/W	4
Junction-to-case thermal resistance	$R_{\theta JC}$	< 0.1	°C/W	5

Notes:
1. Junction temperature is a function of die size, on-chip power dissipation, package thermal resistance, mounting site (board) temperature, ambient temperature, air flow, power dissipation of other components on the board, and board thermal resistance.
2. Per JEDEC JESD51-2 with the single-layer board (JESD51-3) horizontal.
3. Per JEDEC JESD51-6 with the board (JESD51-7) horizontal.
4. Thermal resistance between the die and the printed-circuit board per JEDEC JESD51-8. Board temperature is measured on the top surface of the board near the package.
5. This is the thermal resistance between die and case top surface as measured by the cold plate method (MIL SPEC-883 Method 1012.1) with the calculated case temperature. Actual thermal resistance is less than 0.1 °C/W.

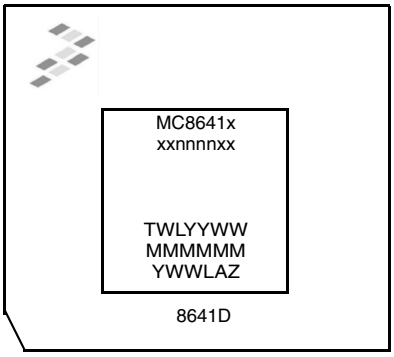
19.2 Thermal Management Information

This section provides thermal management information for the high coefficient of thermal expansion (HCTE) package for air-cooled applications. Proper thermal control design is primarily dependent on the system-level design—the heat sink, airflow, and thermal interface material. The MPC8641 implements several features designed to assist with thermal management, including the temperature diode. The temperature diode allows an external device to monitor the die temperature in order to detect excessive temperature conditions and alert the system; see Section 19.2.4, “Temperature Diode,” for more information.

To reduce the die-junction temperature, heat sinks are required; due to the potential large mass of the heat sink, attachment through the printed-circuit board is suggested. In any implementation of a heat sink solution, the force on the die should not exceed ten pounds force (45 newtons). Figure 59 shows a spring clip through the board. Occasionally the spring clip is attached to soldered hooks or to a plastic backing structure. Screw and spring arrangements are also frequently used.

21.2 Part Marking

Parts are marked as the example shown in Figure 70.



NOTE:
TWLYYWW is the test code
MMMMMM is the M00 (mask) number.
YWWLAZ is the assembly traceability code.

Figure 70. Part Marking for FC-CBGA Device

22 Document Revision History

Table 76 provides a revision history for the MPC8641D hardware specification.

Table 76. Document Revision History

Revision	Date	Substantive Change(s)
3	05/2014	• Updated the Serial RapidIO equation in Section 4.4, “Platform Frequency Requirements for PCI-Express and Serial RapidIO” • Updated Section 19.2.4, “Temperature Diode,” by removing the ideality factor value. • Added VJ package type designator and footnotes to Table 74, “Part Numbering Nomenclature” and Section 16.1, “Package Parameters for the MPC8641.”
2	07/2009	• Added note 8 to Table 49, “Differential Transmitter (TX) Output Specifications.” • Added Revision E to Table 74, “Part Numbering Nomenclature.”
1	11/2008	• Added Section 4.4, “Platform Frequency Requirements for PCI-Express and Serial RapidIO.” • Removed the statement “Note that core processor speed of 1500 MHz is only available for the MPC8641D (dual core)” from Note 2 in Table 74 because a 1500 MHz core is offered for both MPC8641D (dual core) and MPC8641 (single core). • Added Note 8 to Figure 57 and Figure 58.
0	07/2008	• Initial Release